

# **Notice of References Cited**

Application/Control No.

08/811,742

Applicant(s)/Patent Under  
Reexamination  
ZHANG ET AL.

Examiner

Khiem D Nguyen

Art Unit

2823

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-140915	05-1990	Japan	Hideaki Oka	H01L 21/20
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages			
	U	A. Y. Kuznetsov et al. Microsc. Semicond. Mater. Conf. '93 Proc. in inst. Phys. Conf. 134(4)(1993)191. "Silicide precipitate formation and solid phase regrowth of Ni+ implanted a-Si"			
	V				
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	X				

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